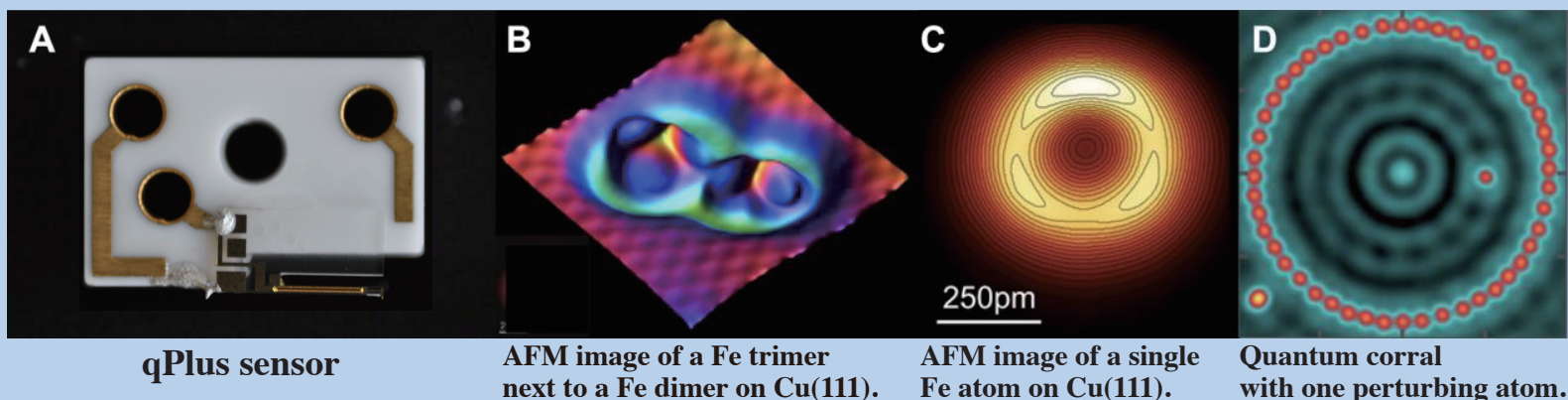


The International Workshop on AFM/STM Using qPlus Sensors and Related Techniques (qPlus Workshop 2026)

October 29–30, 2026

The main conference room of the NanoLSI, Kanazawa University



qPlus sensors have successfully opened the field of nano- and atomic-scale surface observation and characterization based on scanning probe microscopy techniques and have delivered significant scientific and technological advances.

This workshop will bring together researchers working on AFM/STM using qPlus sensors and related techniques to discuss recent advances, experimental techniques, instrumentation, and future developments.

We warmly welcome you to join us and attend the workshop!

Co-Chairs

Toyoko Arai (Kanazawa University)

Franz J. Giessibl (University of Regensburg / Kanazawa University)

Invited Speakers

Franz J. Giessibl (University of Regensburg / Kanazawa University)

Jascha Repp (University of Regensburg)

Takashi Ichii (Kyoto University)

Shigeki Kawai (National Institute for Materials Science)

Toshu An (Japan Advanced Institute of Science and Technology)

Masayuki Abe (The University of Osaka)

Yuji Miyato (Ryukoku University)

Hiroyuki Mogi (University of Tsukuba)

Yuuki Yasui (The University of Tokyo)

Norio Okabayashi (Kanazawa University)

Hiroaki Ooe (Yokohama City University)

Mikihiro Shibata (Kanazawa University)



**Prof. Franz J. Giessibl
at Kanazawa University**

Contact: arai@se.kanazawa-u.ac.jp

Co-Organizer:

Kanazawa University J-PEAKS

nanoLSI,
Kanazawa University

Supporting Organization:

Next Generation Nanoprobe
Technology Committee

Thin Film and Surface
Physics Division of JSAP

